

Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,532	NAKAYAMA, MASATOSHI
Examiner	Art Unit
Tianjie Chen	2652

	SEAR	CHED	
Class	Subclass	Date	Examiner
360	122		
	126		
	234.5		
	235.2		
216	22	5/23/2005	TJ

ERFERENC	NCE SEARCHED		
Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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